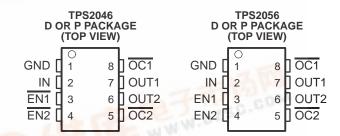
features

- 135-mΩ -Maximum (5-V Input) High-Side
 MOSFET Switch
- 250 mA Continuous Current per Channel
- Independent Short-Circuit and Thermal Protection With Overcurrent Logic Output
- Operating Range . . . 2.7-V to 5.5-V
- Logic-Level Enable Input
- 2.5-ms Typical Rise Time
- Undervoltage Lockout
- 10 μA Maximum Standby Supply Current
- Bidirectional Switch
- Available in 8-pin SOIC and PDIP Packages
- Ambient Temperature Range, –40°C to 85°C
- 2-kV Human-Body-Model, 200-V Machine-Model ESD Protection

typical applications

- Notebook, Desktop and Palmtop PCs
- Monitors, Keyboards, Scanners, and Printers
- Digital Cameras, Phones, and PBXs
- Hot-Insertion Applications



description

The TPS2046 and TPS2056 dual power-distribution switches are intended for applications where heavy capacitive loads and short circuits are likely. These devices incorporate in single packages two 135-m Ω N-channel MOSFET high-side power switches for power-distribution systems that require multiple power switches. Each switch is controlled by a logic enable compatible with 5-V and 3-V logic. Gate drive is provided by an internal charge pump that controls the power-switch rise times and fall times to minimize current surges during switching. The charge pump requires no external components and allows operation from supplies as low as 2.7 V.

When the output load exceeds the current-limit threshold or a short is present, the TPS2046 and TPS2056 limit the output current to a safe level by switching into a constant-current mode, pulling the overcurrent (\overline{OCx}) logic output low. When continuous heavy overloads and short circuits increase the power dissipation in the switch causing the junction temperature to rise, a thermal protection circuit shuts off the switch in overcurrent to prevent damage. Recovery from a thermal shutdown is automatic once the device has cooled sufficiently. Internal circuitry ensures the switch remains off until valid input voltage is present.

The TPS2046 and TPS2056 are designed to limit at 0.44-A load. These power distribution switches, available in 8-pin small-outline integrated circuit (SOIC) and 8-pin plastic dual-in-line packages (PDIP), operate over an ambient temperature range of –40°C to 85°C.

AVAILABLE OPTIONS

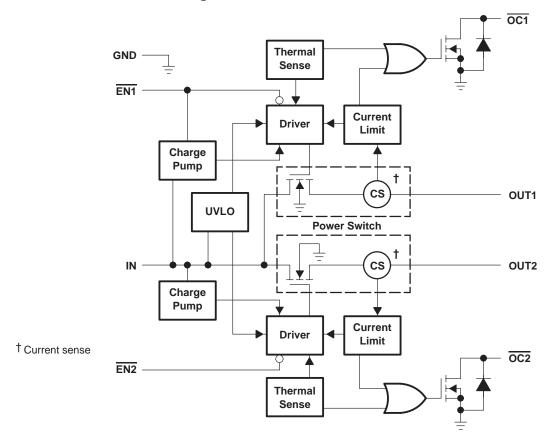
ſ			RECOMMENDED MAXIMUM CONTINUOUS	TYPICAL SHORT-CIRCUIT CURRENT	PACKAGED DEVICES			
	TA	ENABLE	LOAD CURRENT (A)	LIMIT AT 25°C (A)	SOIC (D)†	PDIP (P)		
	–40°C to 85°C	Active low	0.25	0.44	TPS2046D	TPS2046P		
Ì	-40°C to 85°C	Active high	0.25	0.44	TPS2056D	TPS2056P		

[†] The D package is available taped and reeled. Add an R suffix to device type (e.g., TPS2046DR)

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



TPS2046 functional block diagram



Terminal Functions

	TERMINAL	_		
	NO.		1/0	DESCRIPTION
NAME	DO	R P] "/	DESCRIPTION
	TPS2046	TPS2056		
EN1	3	-	I	Enable input. Logic low turns on power switch, IN-OUT1.
EN2	4	-	- 1	Enable input. Logic low turns on power switch, IN-OUT2.
EN1	l1 – 3		- 1	Enable input. Logic high turns on power switch, IN-OUT1.
EN2	ı	4	ı	Enable input. Logic high turns on power switch, IN-OUT2.
GND	1	1	- 1	Ground
IN	2	2	- 1	Input voltage
OC1	8	8	0	Overcurrent. Logic output active low, for power switch, IN-OUT1
OC2	5	5	0	Overcurrent. Logic output active low, for power switch, IN-OUT2
OUT1 7 7		0	Power-switch output	
OUT2 6 6		0	Power-switch output	



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detailed description

power switch

The power switch is an N-channel MOSFET with a maximum on-state resistance of 135 m Ω (V_{I(IN)} = 5 V). Configured as a high-side switch, the power switch prevents current flow from OUTx to IN and IN to OUTx when disabled. The power switch can supply a minimum of 250 mA per switch.

charge pump

An internal charge pump supplies power to the driver circuit and provides the necessary voltage to pull the gate of the MOSFET above the source. The charge pump operates from input voltages as low as 2.7 V and requires very little supply current.

driver

The driver controls the gate voltage of the power switch. To limit large current surges and reduce the associated electromagnetic interference (EMI) produced, the driver incorporates circuitry that controls the rise times and fall times of the output voltage. The rise and fall times are typically in the 2-ms to 4-ms range.

enable (ENx or ENx)

The logic enable disables the power switch and the bias for the charge \underline{pump} , driver, and other circuitry to reduce the supply current to less than 10 μ A when a logic high is present on \underline{ENx} (TPS2046) or a logic low is present on \underline{ENx} (TPS2056). A logic zero input on \underline{ENx} or logic high on \underline{ENx} restores bias to the drive and control circuits and turns the power on. The enable input is compatible with both TTL and CMOS logic levels.

overcurrent (OCx)

The \overline{OCx} open-drain output is asserted (active low) when an overcurrent or overtemperature condition is encountered. The output will remain asserted until the overcurrent or overtemperature condition is removed.

current sense

A sense FET monitors the current supplied to the load. The sense FET measures current more efficiently than conventional resistance methods. When an overload or short circuit is encountered, the current-sense circuitry sends a control signal to the driver. The driver in turn reduces the gate voltage and drives the power FET into its saturation region, which switches the output into a constant current mode and holds the current constant while varying the voltage on the load.

thermal sense

The TPS2046 and TPS2056 implement a dual-threshold thermal trip to allow fully independent operation of the power distribution switches. In an overcurrent or short-circuit condition the junction temperature rises. When the die temperature rises to approximately 140° C, the internal thermal sense circuitry checks to determine which power switch is in an overcurrent condition and turns off that switch, thus isolating the fault without interrupting operation of the adjacent power switches. Hysteresis is built into the thermal sense, and after the device has cooled approximately 20 degrees, the switch turns back on. The switch continues to cycle off and on until the fault is removed. The (\overline{OCx}) open-drain output is asserted (active low) when overtemperature or overcurrent occurs.

undervoltage lockout

A voltage sense circuit monitors the input voltage. When the input voltage is below approximately 2 V, a control signal turns off the power switch.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Input voltage range, V _{I(IN)} (see Note1)	0.3 V to 6 V
Output voltage range, $V_{O(OUTx)}$ (see Note1)	$-0.3 \text{ V to V}_{I(IN)} + 0.3 \text{ V}$
Input voltage range, $V_{I(ENx)}$ or $V_{I(ENx)}$	
Continuous output current, I _{O(OUTx)}	
Continuous total power dissipation	
Operating virtual junction temperature range, T _J	–40°C to 125°C
Storage temperature range, T _{stq}	–65°C to 150°C
Lead temperature soldering 1,6 mm (1/16 inch) from case for 10 seconds	
Electrostatic discharge (ESD) protection: Human body model MIL-STD-883C	2 kV
Machine model	0.2 kV

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltages are with respect to GND.

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{\scriptsize A}} \le 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING
D	725 mW	5.8 mW/°C	464 mW	377 mW
Р	1175 mW	9.4 mW/°C	752 mW	611 mW

recommended operating conditions

	TPS2	2046	TPS2	UNIT	
	MIN	MAX	MIN	MAX	UNIT
Input voltage, VI(IN)	2.7	5.5	2.7	5.5	V
Input voltage, VI(ENx) or VI(ENx)	0	5.5	0	5.5	V
Continuous output current, IO(OUTx)	0	250	0	250	mA
Operating virtual junction temperature, T _J	-40	125	-40	125	°C



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electrical characteristics over recommended operating junction temperature range, $V_{I(IN)} = 5.5 \text{ V}$, $I_{O} = \text{rated current}$, $V_{I(ENx)} = 0 \text{ V}$, $V_{I(ENx)} = \text{Hi}$ (unless otherwise noted)

power switch

PARAMETER		TEST COL	UDITIONST	Т	PS2046		Т	PS2056		UNIT
	PARAMETER	TEST COI	NDITIONS†	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
		$V_{I(IN)} = 5 \text{ V},$ $I_{O} = 0.1 \text{ A}$	$T_J = 25^{\circ}C$,		80	95		80	95	
	Static drain-source on-state resistance, 5-V operation	$V_{I(IN)} = 5 \text{ V},$ $I_{O} = 0.1 \text{ A}$	T _J = 85°C,		90	120		90	120	
		$V_{I(IN)} = 5 \text{ V},$ $I_{O} = 0.1 \text{ A}$	T _J = 125°C,		100	135		100	135	mΩ
rDS(on)		$V_{I(IN)} = 3.3 \text{ V},$ $I_{O} = 0.1 \text{ A}$	T _J = 25°C,		85	105		85	105	
	Static drain-source on-state resistance, 3.3-V operation	$V_{I(IN)} = 3.3 \text{ V},$ $I_{O} = 0.1 \text{ A}$	T _J = 85°C,		100	135		100	135	
		$V_{I(IN)} = 3.3 \text{ V},$ $I_{O} = 0.1 \text{ A}$	T _J = 125°C,		115	150		115	150	
	Digo timo, output	$V_{I(IN)} = 5.5 \text{ V},$ $C_{L} = 1 \mu\text{F},$	$T_J = 25^{\circ}C$, $R_L = 20 \Omega$		2.5			2.5		ms
t _r	Rise time, output	$V_{I(IN)} = 2.7 \text{ V},$ $C_L = 1 \mu\text{F},$	$T_J = 25^{\circ}C$, $R_L = 20 \Omega$		3			3		1115
+.	Fall time, output	$V_{I(IN)} = 5.5 \text{ V},$ $C_L = 1 \mu\text{F},$	$T_J = 25^{\circ}C$, $R_L = 20 \Omega$		4.4			4.4		me
tf	r an ume, output	$V_{I(IN)} = 2.7 \text{ V},$ $C_L = 1 \mu\text{F},$	$T_J = 25^{\circ}C$, $R_L = 20 \Omega$		2.5			2.5		ms

[†] Pulse-testing techniques maintain junction temperature close to ambient temperature; thermal effects must be taken into account separately.

enable input ENx or ENx

	PARAMETER		TEST CONDITIONS	1	PS2046	6	1	UNIT		
	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
VIH	High-level input voltag	е	$2.7 \text{ V} \le \text{V}_{\text{I(IN)}} \le 5.5 \text{ V}$	2			2			V
\/	V _{IL} Low-level input voltage		$4.5 \text{ V} \le \text{V}_{\text{I(IN)}} \le 5.5 \text{ V}$			0.8			0.8	V
\ \IL			2.7 V≤ V _{I(IN)} ≤ 4.5 V			0.4			0.4	
1.	lanut aurrant	TPS2046	$V_{I}(\overline{ENx}) = 0 \text{ V or } V_{I}(\overline{ENx}) = V_{I}(IN)$	-0.5		0.5				4
'	Input current	TPS2056	$V_{I(ENx)} = V_{I(IN)}$ or $V_{I(ENx)} = 0$ V				-0.5		0.5	μΑ
ton Turn-on time		$C_L = 100 \mu\text{F}, R_L = 20 \Omega$			20			20	ms	
toff	Turn-off time		$C_L = 100 \mu\text{F}, R_L = 20 \Omega$			40			40	

current limit

	PARAMETER	TEST CONDITIONST	٦	TPS2046		TPS2056			UNIT	
	FARAMETER	TEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	_ OIVIII	
los		V _{I(IN)} = 5 V, OUT connected to GND, Device enable into short circuit.	0.345	0.44	0.525	0.345	0.44	0.525	А	

[†] Pulse-testing techniques maintain junction temperature close to ambient temperature; thermal effects must be taken into account separately.



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electrical characteristics over recommended operating junction temperature range, $V_{I(IN)} = 5.5 \text{ V}$, $I_{O} = \text{rated current}$, $V_{I(ENx)} = 0 \text{ V}$, $V_{I(ENx)} = \text{Hi}$ (unless otherwise noted) (continued)

supply current

PARAMETE		TEST CO	NDITIONS		Т	PS2046		Т	PS2056		UNIT	
R		1231 60	NDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	UNIT	
Supply		L. —	T _J = 25°C	TPS2046		0.015	1					
current,	No Load on OUTx	$V_{I}(\overline{ENx}) = V_{I}(IN)$	-40 °C $\leq T_J \leq 125$ °C	17 32040			10				μА	
low-level		V _I (ENx) = 0 V	T _J = 25°C	TPS2056					0.015	1	μΛ	
output			$-40^{\circ}\text{C} \le \text{T}_{\text{J}} \le 125^{\circ}\text{C}$							10		
Supply		\/ 	T _J = 25°C	TPS2046		80	100					
current,	No Load	$V_{I}(\overline{ENx}) = 0 V$	$-40^{\circ}\text{C} \le \text{T}_{\text{J}} \le 125^{\circ}\text{C}$	17 32040		100]	
high-level	on OUTx		V.(=>) = V.(>)	T _J = 25°C	TPS2056					80	100	μΑ
output		$V_{I(ENx)} = V_{I(IN)}$	$-40^{\circ}\text{C} \le \text{T}_{\text{J}} \le 125^{\circ}\text{C}$	1732030					100			
Leakage	OUTx connected	$V_{I}(\overline{ENx}) = V_{I}(IN)$	$-40^{\circ}C \le T_{J} \le 125^{\circ}C$	TPS2046		100						
current	to ground	$V_{I(ENx)} = 0 V$	$-40^{\circ}\text{C} \le \text{T}_{J} \le 125^{\circ}\text{C}$	TPS2056					100		μΑ	
Reverse	IN = high	$V_{I}(\overline{ENx}) = 0 V$	T 25°C	TPS2046		0.3						
leakage current	impedance	11=25%	1 J = 25 C	TPS2056			·		0.3		μΑ	

undervoltage lockout

PARAMETER	TEST CONDITIONS	T CONDITIONS			TPS2056			UNIT
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNII
Low-level input voltage		2		2.5	2		2.5	V
Hysteresis	T _J = 25°C		100			100		mV

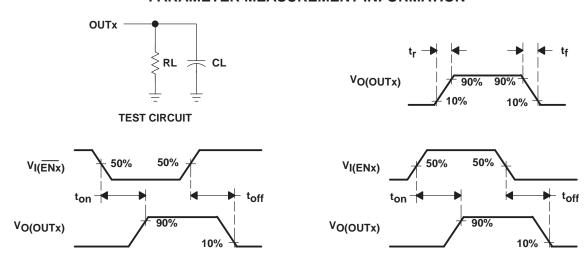
overcurrent OCx

PARAMETER	TEST CONDITIONS	Т	PS2046	1	Т	UNIT		
PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	ONIT
Sink current [†]	V _O = 5 V			10			10	mA
Output low voltage	$I_O = 5 \text{ mA}, V_{OL(OCx)}$			0.5			0.5	V
Off-state current [†]	$V_O = 5 \text{ V}, V_O = 3.3 \text{ V}$			1			1	μА

[†] Specified by design, not production tested.



PARAMETER MEASUREMENT INFORMATION



VOLTAGE WAVEFORMS

Figure 1. Test Circuit and Voltage Waveforms

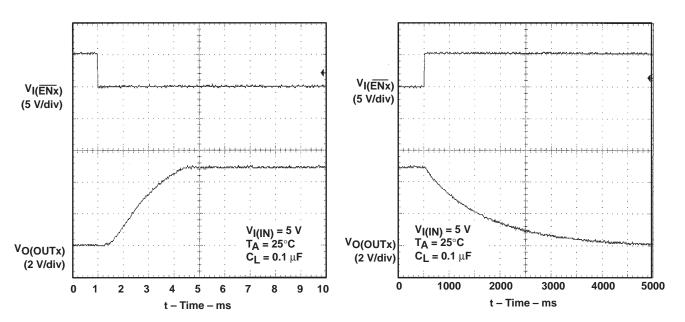
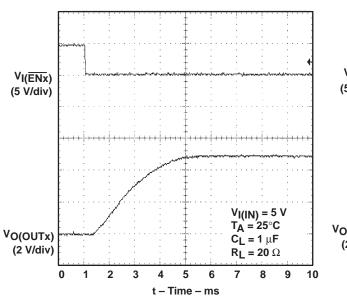


Figure 2. Turnon Delay and Rise Time with 0.1- μ F Load

Figure 3. Turnoff Delay and Fall Time with 0.1-µF Load



PARAMETER MEASUREMENT INFORMATION



 $\begin{array}{c} V_{\text{I}(\overline{\text{ENx}})} \\ V_{\text{I}(\text{IN})} = 5 \, \text{V} \\ T_{\text{A}} = 25^{\circ}\text{C} \\ \text{CL} = 1 \, \mu\text{F} \\ \text{RL} = 20 \, \Omega \\ \\ 0 \quad 2 \quad 4 \quad 6 \quad 8 \quad 10 \quad 12 \quad 14 \quad 16 \quad 18 \quad 20 \\ \\ \text{t-Time-ms} \end{array}$

Figure 4. Turnon Delay and Rise Time with 1-μF Load

Figure 5. Turnoff Delay and Fall Time with 1-μF Load

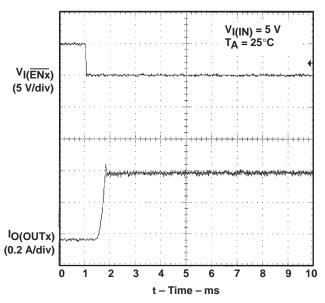


Figure 6. TPS2046, Short-Circuit Current, Device Enabled into Short

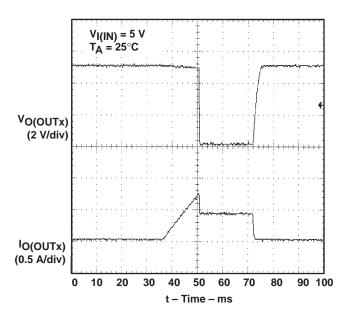


Figure 7. TPS2046, Threshold Trip Current with Ramped Load on Enabled Device



PARAMETER MEASUREMENT INFORMATION

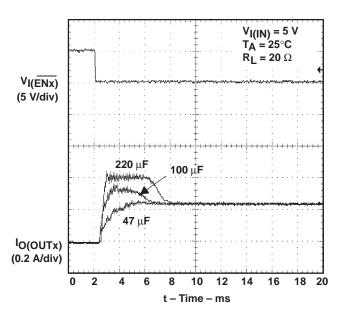


Figure 8. Inrush Current with 220- μ F, 100- μ F and 47- μ F Load Capacitance

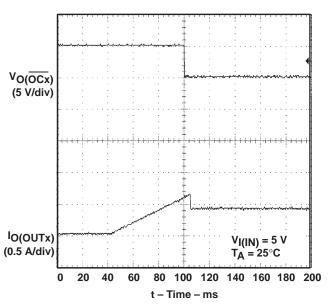


Figure 9. Ramped Load on Enabled Device

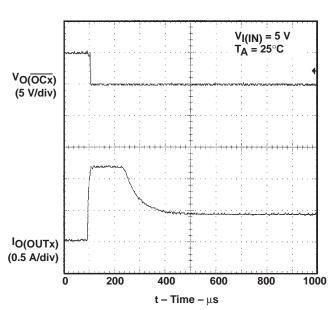


Figure 10. 4- Ω Load Connected to Enabled Device

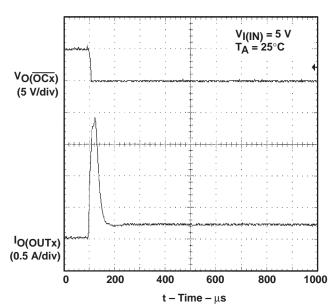
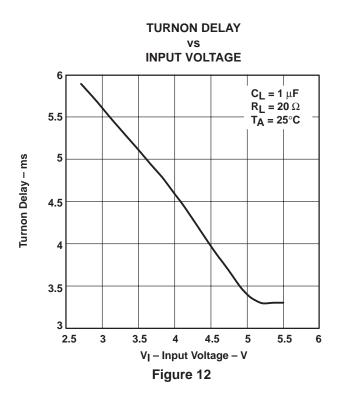
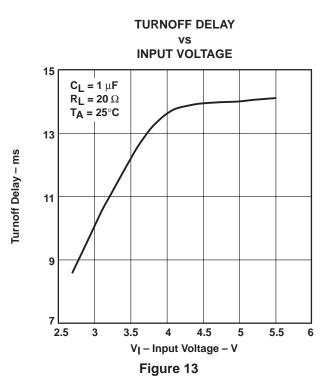
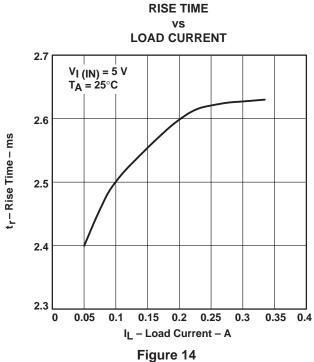
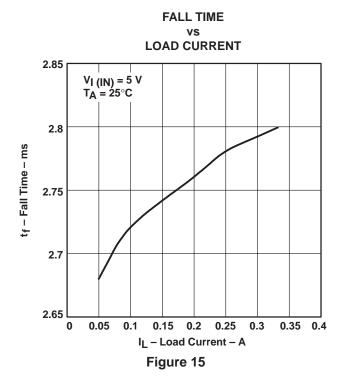


Figure 11. 1- Ω Load Connected to Enabled Device



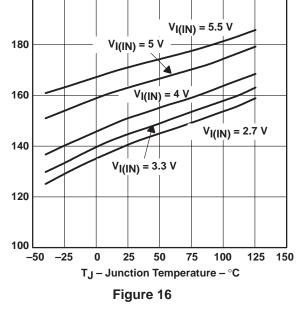






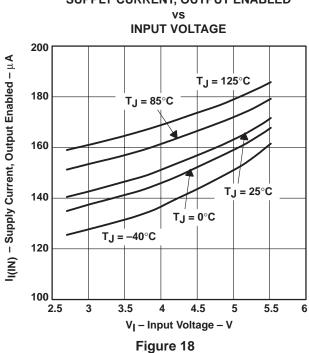


SUPPLY CURRENT, OUTPUT ENABLED JUNCTION TEMPERATURE 200 $V_{I(IN)} = 5.5 V$ $V_{I(IN)} = 5 V$ $V_{I(IN)} = 4 V$ $V_{I(IN)} = 2.7 V$ $V_{I(IN)} = 3.3 V$

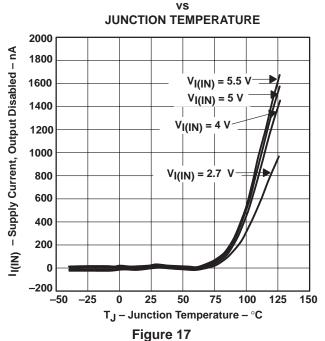


 $I_{I(IN)}-Supply$ Current, Output Enabled $-\mu A$

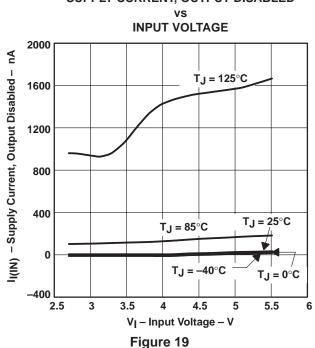
SUPPLY CURRENT, OUTPUT ENABLED



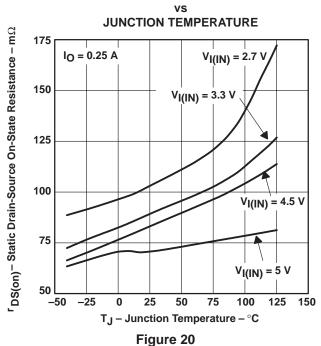
SUPPLY CURRENT, OUTPUT DISABLED



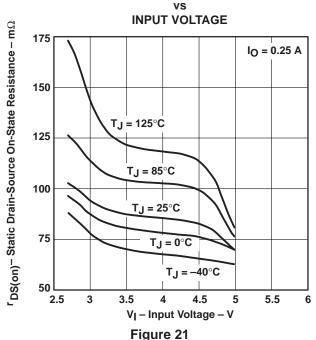
SUPPLY CURRENT, OUTPUT DISABLED



STATIC DRAIN-SOURCE ON-STATE RESISTANCE



STATIC DRAIN-SOURCE ON-STATE RESISTANCE



INPUT-TO-OUTPUT VOLTAGE

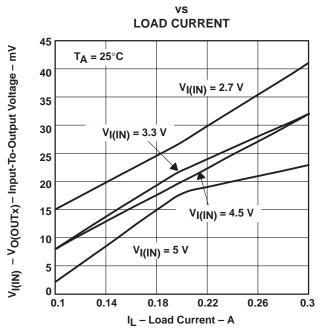
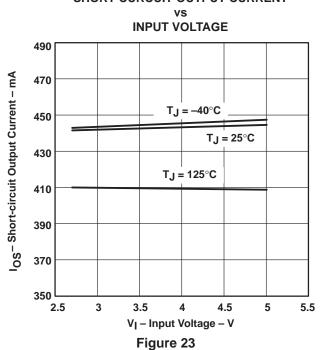
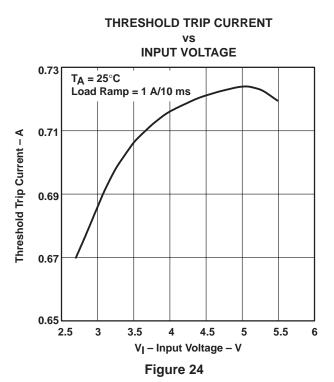


Figure 22

SHORT-CURCUIT OUTPUT CURRENT







UNDERVOLTAGE LOCKOUT
vs

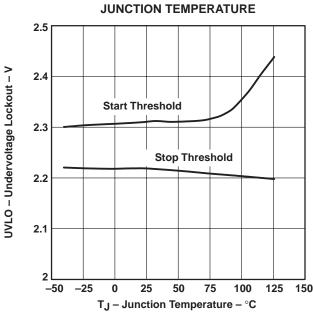


Figure 26

SHORTCIRCUIT OUTPUT CURRENT vs
JUNCTION TEMPERATURE

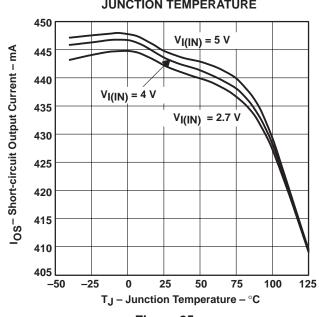


Figure 25



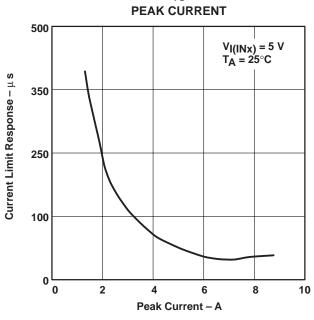
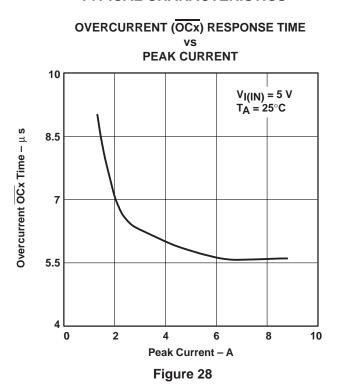


Figure 27



APPLICATION INFORMATION

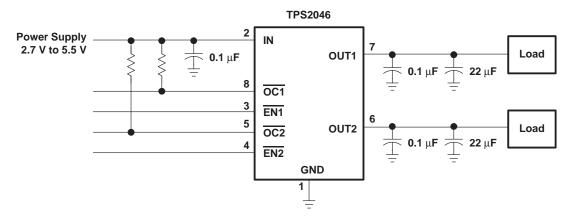


Figure 29. Typical Application

power-supply considerations

A 0.01- μF to 0.1- μF ceramic bypass capacitor between IN and GND, close to the device, is recommended. Placing a high-value electrolytic capacitor on the output pin(s) is recommended when the output load is heavy. This precaution reduces power-supply transients that may cause ringing on the input. Additionally, bypassing the output with a 0.01- μF to 0.1- μF ceramic capacitor improves the immunity of the device to short-circuit transients.



APPLICATION INFORMATION

overcurrent

A sense FET is employed to check for overcurrent conditions. Unlike current-sense resistors, sense FETs do not increase the series resistance of the current path. When an overcurrent condition is detected, the device maintains a constant output current and reduces the output voltage accordingly. Complete shutdown occurs only if the fault is present long enough to activate thermal limiting.

Three possible overload conditions can occur. In the first condition, the output has been shorted before the device is enabled or before $V_{I(IN)}$ has been applied (see Figure 6). The TPS2046 and TPS2056 sense the short and immediately switch into a constant-current output.

In the second condition, the short occurs while the device is enabled. At the instant the short occurs, very high currents may flow for a short time before the current-limit circuit can react. After the current-limit circuit has tripped (reached the overcurrent trip threshhold) the device switches into constant-current mode.

In the third condition, the load has been gradually increased beyond the recommended operating current. The current is permitted to rise until the current-limit threshold is reached or until the thermal limit of the device is exceeded (see Figure 7). The TPS2046 and TPS2056 are capable of delivering current up to the current-limit threshold without damaging the device. Once the threshold has been reached, the device switches into its constant-current mode.

OCx response

The $\overline{\text{OCx}}$ open-drain output is asserted (active low) when an overcurrent or overtemperature condition is encountered. The output will remain asserted until the overcurrent or overtemperature condition is removed. Connecting a heavy capacitive load to an enabled device can cause momentary false overcurrent reporting from the inrush current flowing through the device, charging the downstream capacitor. An RC filter (see Figure 30) can be connected to the $\overline{\text{OCx}}$ pin to reduce false overcurrent reporting caused by hot-plug switching events or extremely high capacitive loads. Using low-ESR electrolytic capacitors on the output lowers the inrush current flow through the device during hot-plug events by providing a low impedance energy source, thereby reducing erroneous overcurrent reporting.

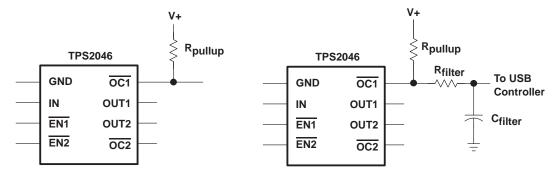


Figure 30. Typical Circuits for OC Pin and RC Filter for Damping Inrush OC Responses



APPLICATION INFORMATION

power dissipation and junction temperature

The low on-resistance on the n-channel MOSFET allows small surface-mount packages, such as SOIC, to pass large currents. The thermal resistances of these packages are high compared to that of power packages; it is good design practice to check power dissipation and junction temperature. The first step is to find $r_{DS(on)}$ at the input voltage and operating temperature. As an initial estimate, use the highest operating ambient temperature of interest and read $r_{DS(on)}$ from Figure 21. Next, calculate the power dissipation using:

$$P_D = r_{DS(on)} \times I^2$$

Finally, calculate the junction temperature:

$$T_J = P_D \times R_{\theta JA} + T_A$$

Where:

 T_A = Ambient Temperature °C $R_{\theta JA}$ = Thermal resistance SOIC = 172°C/W, PDIP = 106°C/W

Compare the calculated junction temperature with the initial estimate. If they do not agree within a few degrees, repeat the calculation, using the calculated value as the new estimate. Two or three iterations are generally sufficient to get a reasonable answer.

thermal protection

Thermal protection prevents damage to the IC when heavy-overload or short-circuit faults are present for extended periods of time. The faults force the TPS2046 and TPS2056 into constant current mode, which causes the voltage across the high-side switch to increase; under short-circuit conditions, the voltage across the switch is equal to the input voltage. The increased dissipation causes the junction temperature to rise to high levels. The protection circuit senses the junction temperature of the switch and shuts it off. Hysteresis is built into the thermal sense circuit, and after the device has cooled approximately 20 degrees, the switch turns back on. The switch continues to cycle in this manner until the load fault or input power is removed.

The TPS2046 and TPS2056 implement a dual thermal trip to allow fully independent operation of the power distribution switches. In an overcurrent or short-circuit condition the junction temperature will rise. Once the die temperature rises to approximately 140°C, the internal thermal sense circuitry checks which power switch is in an overcurrent condition and turns that power switch off, thus isolating the fault without interrupting operation of the adjacent power switch. Should the die temperature exceed the first thermal trip point of 140°C and reach 160°C, both switches turn off. The \overline{OC} open-drain output is asserted (active low) when overtemperature or overcurrent occurs.

undervoltage lockout (UVLO)

An undervoltage lockout ensures that the power switch is in the off state at power up. Whenever the input voltage falls below approximately 2 V, the power switch will be quickly turned off. This facilitates the design of hot-insertion systems where it is not possible to turn off the power switch before input power is removed. The UVLO will also keep the switch from being turned on until the power supply has reached at least 2 V, even if the switch is enabled. Upon reinsertion, the power switch will be turned on with a controlled rise time to reduce EMI and voltage overshoots.



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APPLICATION INFORMATION

Universal Serial Bus (USB) applications

The Universal Serial Bus (USB) interface is a 12-Mb/s, or 1.5-Mb/s, multiplexed serial bus designed for low-to-medium bandwidth PC peripherals (e.g., keyboards, printers, scanners, and mice). The four-wire USB interface is conceived for dynamic attach-detach (hot plug-unplug) of peripherals. Two lines are provided for differential data, and two lines are provided for 5-V power distribution.

USB data is a 3.3-V level signal, but power is distributed at 5 V to allow for voltage drops in cases where power is distributed through more than one hub across long cables. Each function must provide its own regulated 3.3 V from the 5-V input or its own internal power supply.

The USB specification defines the following five classes of devices, each differentiated by power-consumption requirements:

- Hosts/self-powered hubs (SPH)
- Bus-powered hubs (BPH)
- Low-power, bus-powered functions
- High-power, bus-powered functions
- Self-powered functions

Self-powered and bus-powered hubs distribute data and power to downstream functions. The TPS2046 and TPS2056 can provide power-distribution solutions for many of these classes of devices.

bus-powered hubs

Bus-powered hubs obtain all power from upstream ports and often contain an embedded function. The hubs are required to power up with less than one unit load. The BPH usually has one embedded function, and power is always available to the controller of the hub. If the embedded function and hub require more than 100 mA on power up, the power to the embedded function may need to be kept off until enumeration is completed. This can be accomplished by removing power or by shutting off the clock to the embedded function. Power switching the embedded function is not necessary if the aggregate power draw for the function and controller is less than one unit load. The total current drawn by the bus-powered device is the sum of the current to the controller, the embedded function, and the downstream ports, and it is limited to 500 mA from an upstream port.

low-power bus-powered functions and high-power bus-powered functions

Both low-power and high-power bus-powered functions obtain all power from upstream ports; low-power functions always draw less than 100 mA, and high-power functions must draw less than 100 mA at power up and can draw up to 500 mA after enumeration. If the load of the function is more than the parallel combination of 44 Ω and 10 μ F at power up, the device must implement inrush current limiting (see Figure 31).



APPLICATION INFORMATION

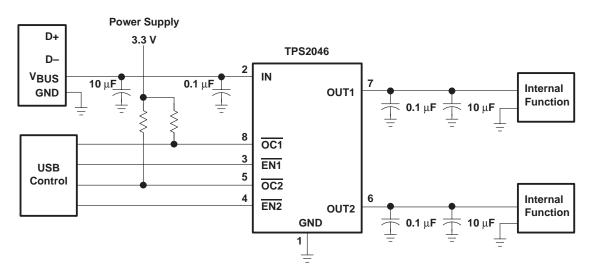


Figure 31. High-Power Bus-Powered Function

USB power-distribution requirements

USB can be implemented in several ways, and, regardless of the type of USB device being developed, several power distribution features must be implemented.

- Bus-Powered Hubs must:
 - Enable/disable power to downstream ports
 - Power up at <100 mA
 - Limit inrush current (<44 Ω and 10 μ F)
- Functions must:
 - Limit inrush currents
 - Power up at <100 mA

The feature set of the TPS2046 and TPS2056 allows them to meet each of these requirements. The integrated current-limiting and overcurrent reporting is required by hosts and self-powered hubs. The logic-level enable and controlled rise times meet the need of both input and output ports on bus-power hubs, as well as the input ports for bus-power functions (see Figure 32).



APPLICATION INFORMATION

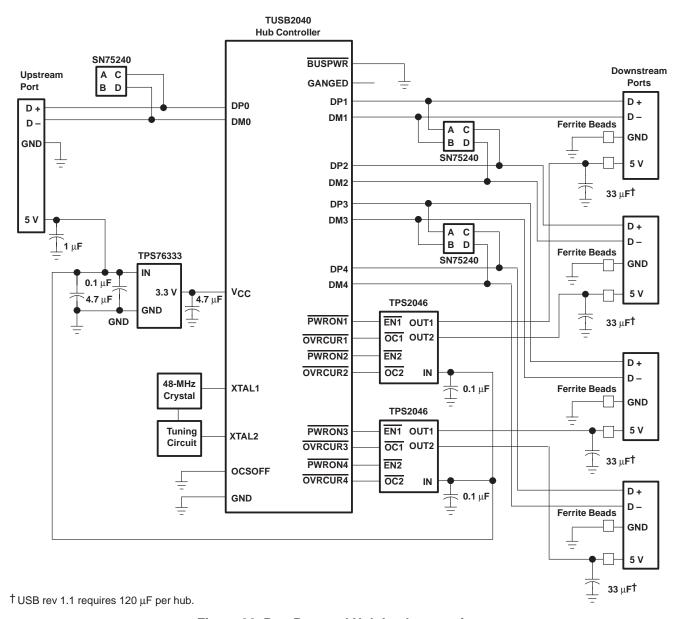


Figure 32. Bus-Powered Hub Implementation



APPLICATION INFORMATION

generic hot-plug applications (see Figure 33)

In many applications it may be necessary to remove modules or pc boards while the main unit is still operating. These are considered hot-plug applications. Such implementations require the control of current surges seen by the main power supply and the card being inserted. The most effective way to control these surges is to limit and slowly ramp the current and voltage being applied to the card, similar to the way in which a power supply normally turns on. Due to the controlled rise times and fall times of the TPS2046 and TPS2056, these devices can be used to provide a softer start-up to devices being hot-plugged into a powered system. The UVLO feature of the TPS2046 and TPS2056 also ensures the switch will be off after the card has been removed, and the switch will be off during the next insertion. The UVLO feature guarantees a soft start with a controlled rise time for every insertion of the card or module.

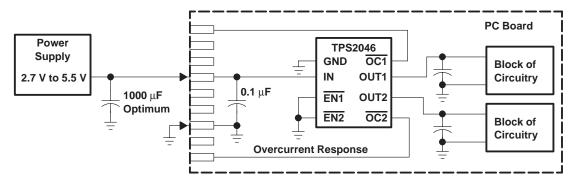


Figure 33. Typical Hot-Plug Implementation

By placing the TPS2046 and TPS2056 between the V_{CC} input and the rest of the circuitry, the input power will reach these devices first after insertion. The typical rise time of the switch is approximately 2.5 ms, providing a slow voltage ramp at the output of the device. This implementation controls system surge currents and provides a hot-plugging mechanism for any device.

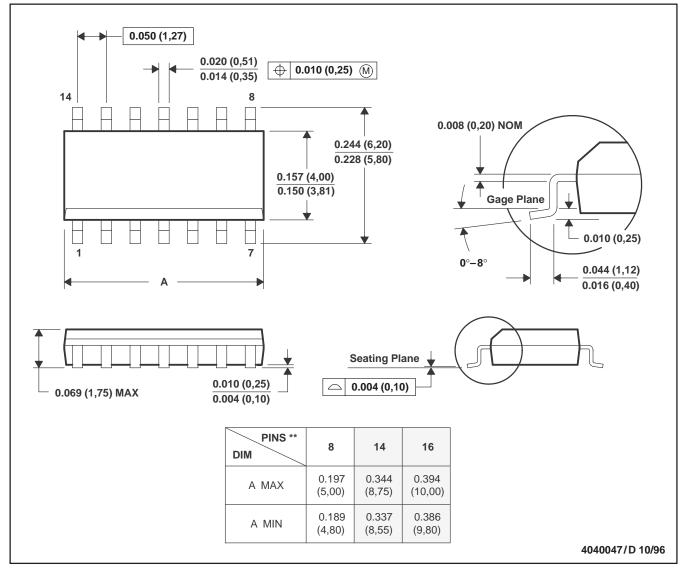


MECHANICAL DATA

D (R-PDSO-G**)

14 PIN SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-012

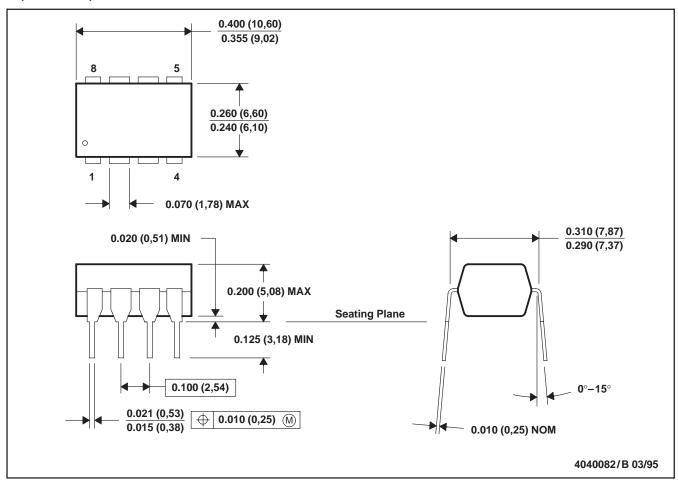


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MECHANICAL DATA

P (R-PDIP-T8)

PLASTIC DUAL-IN-LINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-001



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